

Title (en)  
METHOD FOR PRODUCING SILICON SINGLE CRYSTAL

Title (de)  
VERFAHREN ZUR HERSTELLUNG VON SILICIUM EINKRISTALLEN

Title (fr)  
PROCEDE DE PRODUCTION D'UN CRISTAL UNIQUE DE SILICIUM

Publication  
**EP 1087040 A1 20010328 (EN)**

Application  
**EP 00906720 A 20000306**

Priority  

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- JP 7120899 A 19990317

Abstract (en)  
In a method for producing a silicon single crystal by growing a single crystal ingot while a magnetic field perpendicular to a crystal growth axis is applied to a silicon melt contained in a quartz crucible during pulling of the single crystal from the melt contained in the quartz crucible, the crystal growth is performed so that one of a low temperature region and a high temperature region generated at a surface of the silicon melt contained in the crucible should always cover a solid-liquid interface of the crystal growth, or a ratio of vertical magnetic field component to horizontal magnetic field component for magnetic field strength at the crystal center of the surface of the silicon melt contained in the quartz crucible is controlled to be 0.3 or more and 0.5 or less. There are provided methods for producing a silicon single crystal based on the CZ method in which a horizontal magnetic field is applied, which can produce a silicon single crystal ingot of high uniformity of interstitial oxygen concentration along the growth direction of the grown single crystal with high productivity and high yield. <IMAGE>

IPC 1-7  
**C30B 15/00**; **C30B 29/06**; **C30B 30/04**

IPC 8 full level  
**C30B 15/00** (2006.01); **C30B 15/30** (2006.01); **C30B 30/04** (2006.01)

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